

FIG. 1

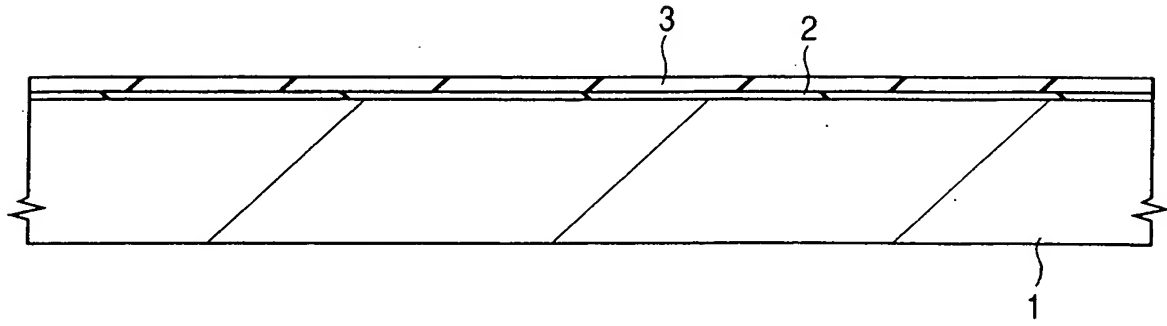


FIG. 2

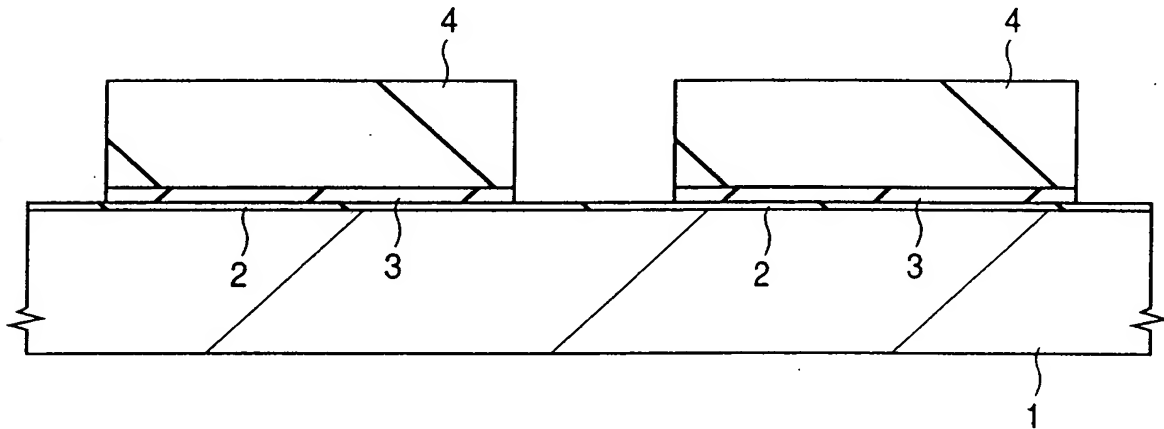


FIG. 3

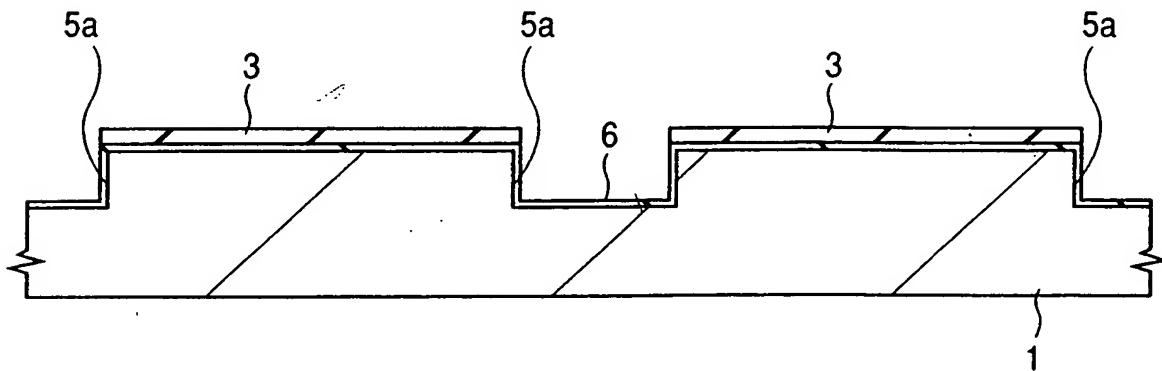


FIG. 4

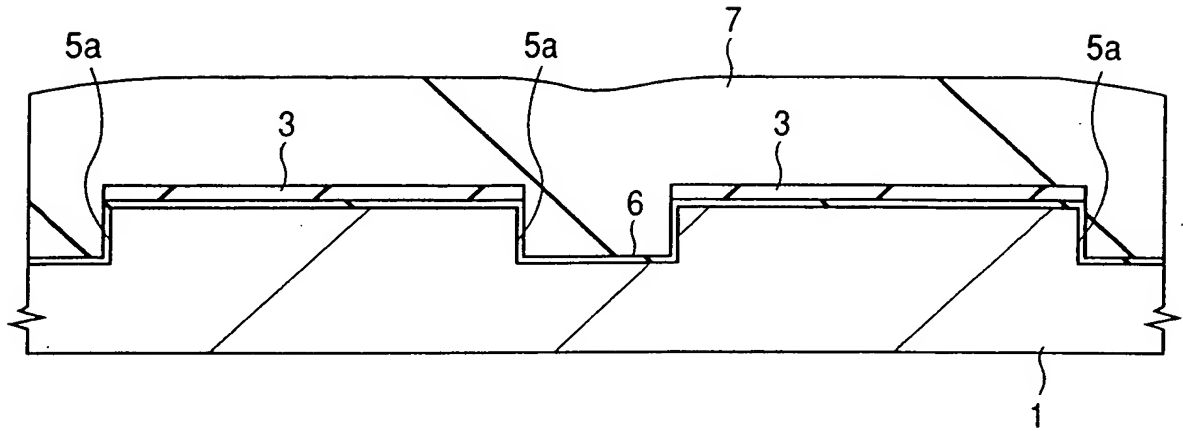


FIG. 5

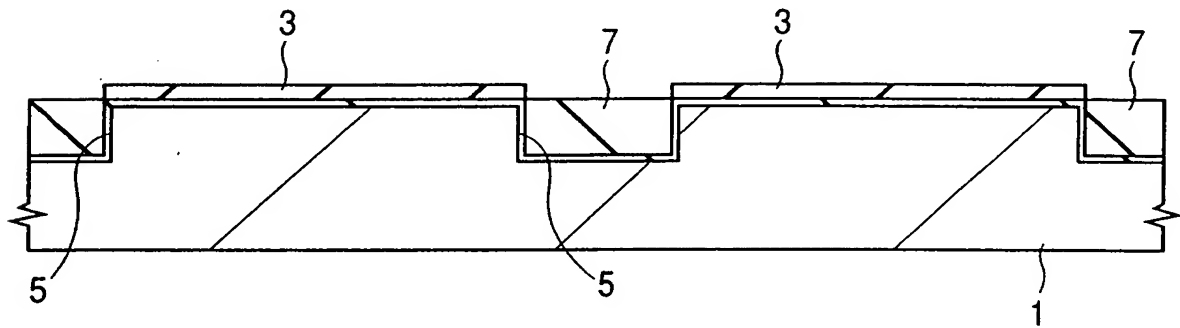


FIG. 6

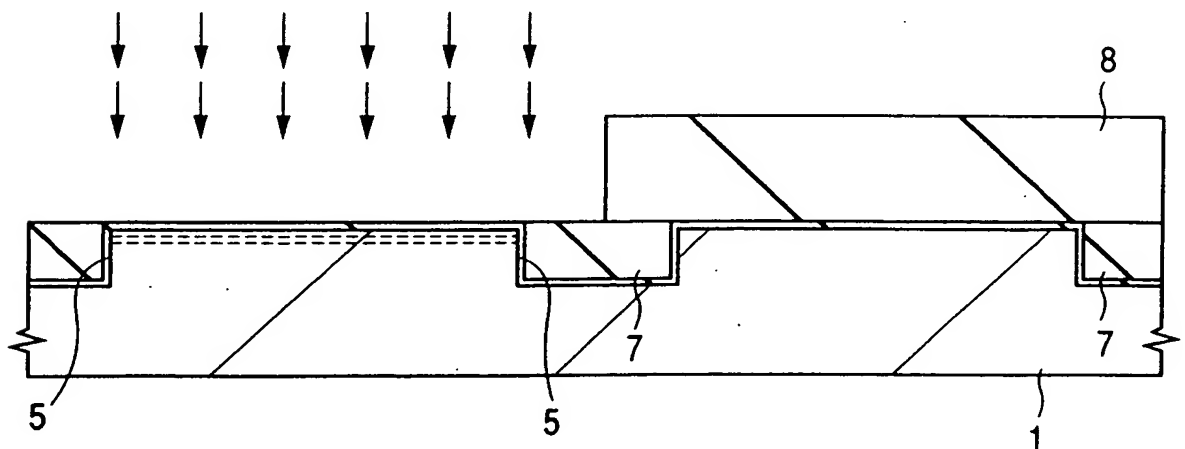


FIG. 7

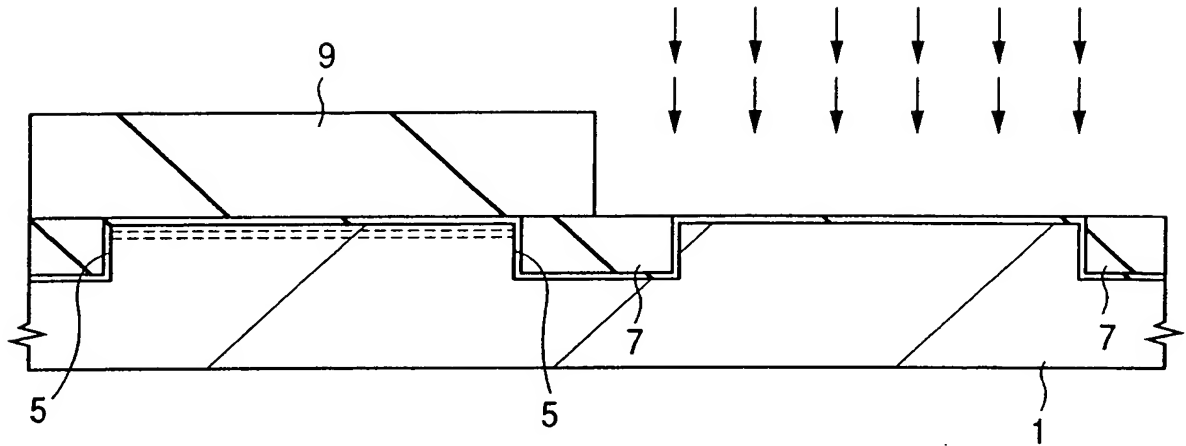


FIG. 8

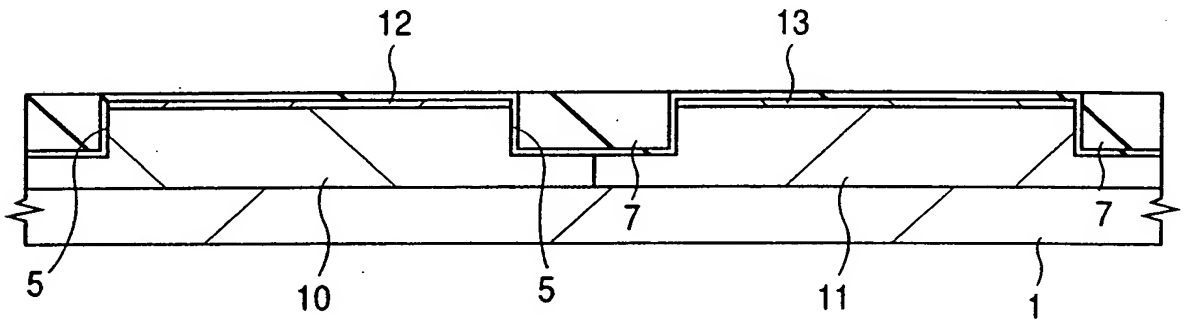


FIG. 10

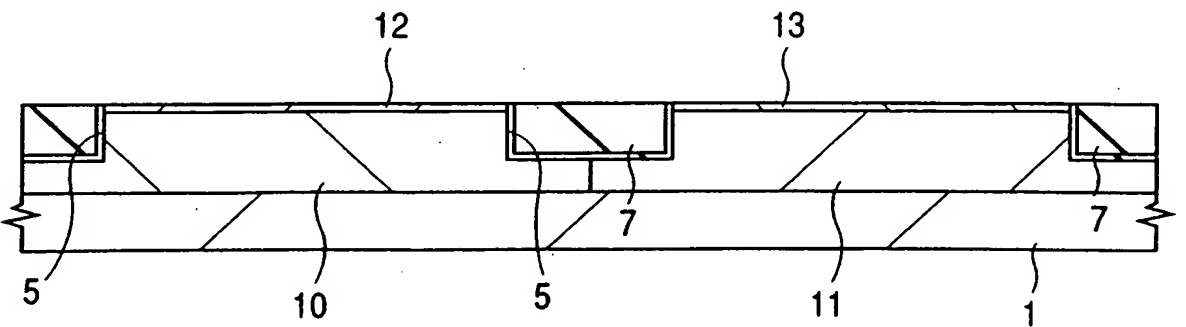


FIG. 9

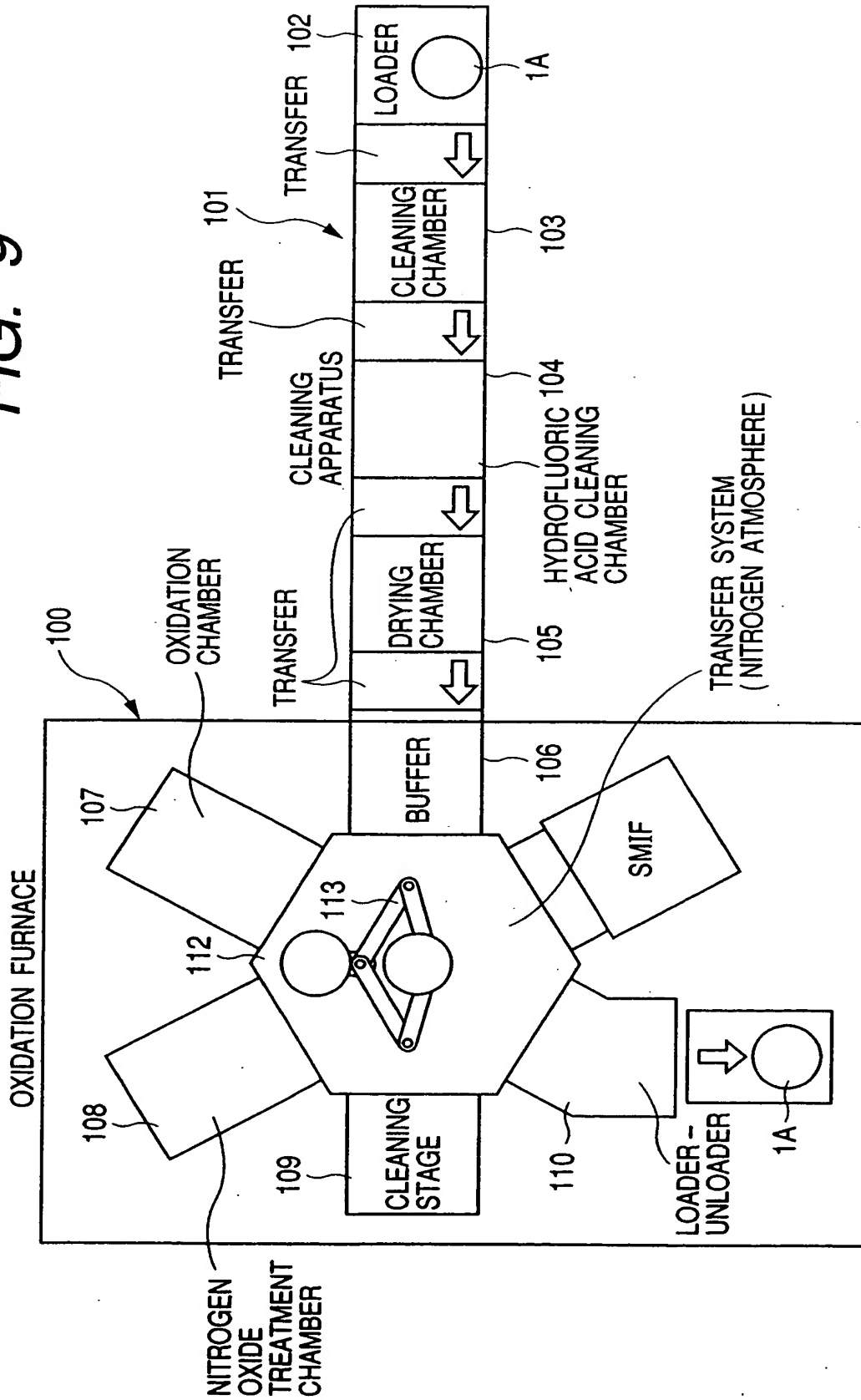


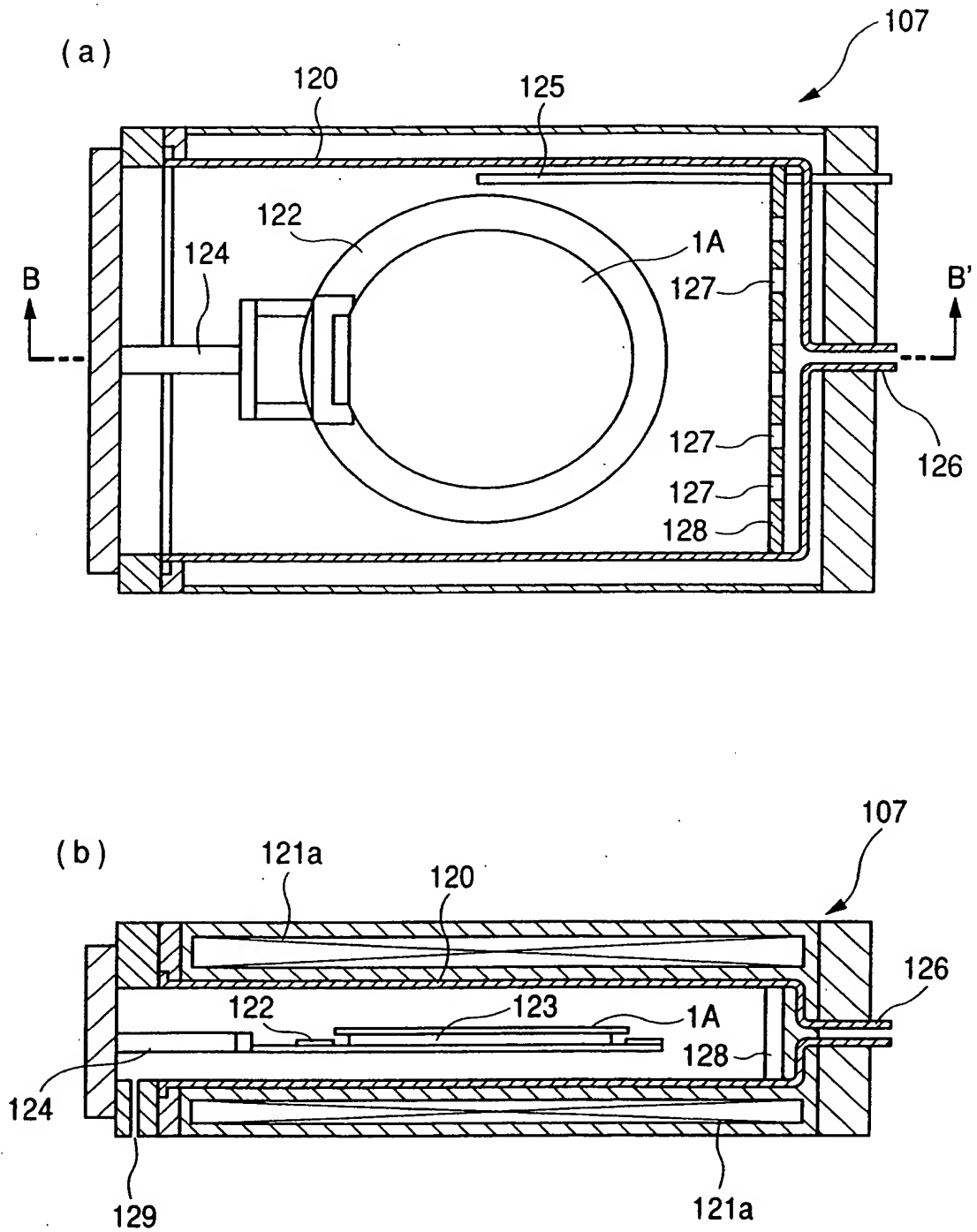
FIG. 11

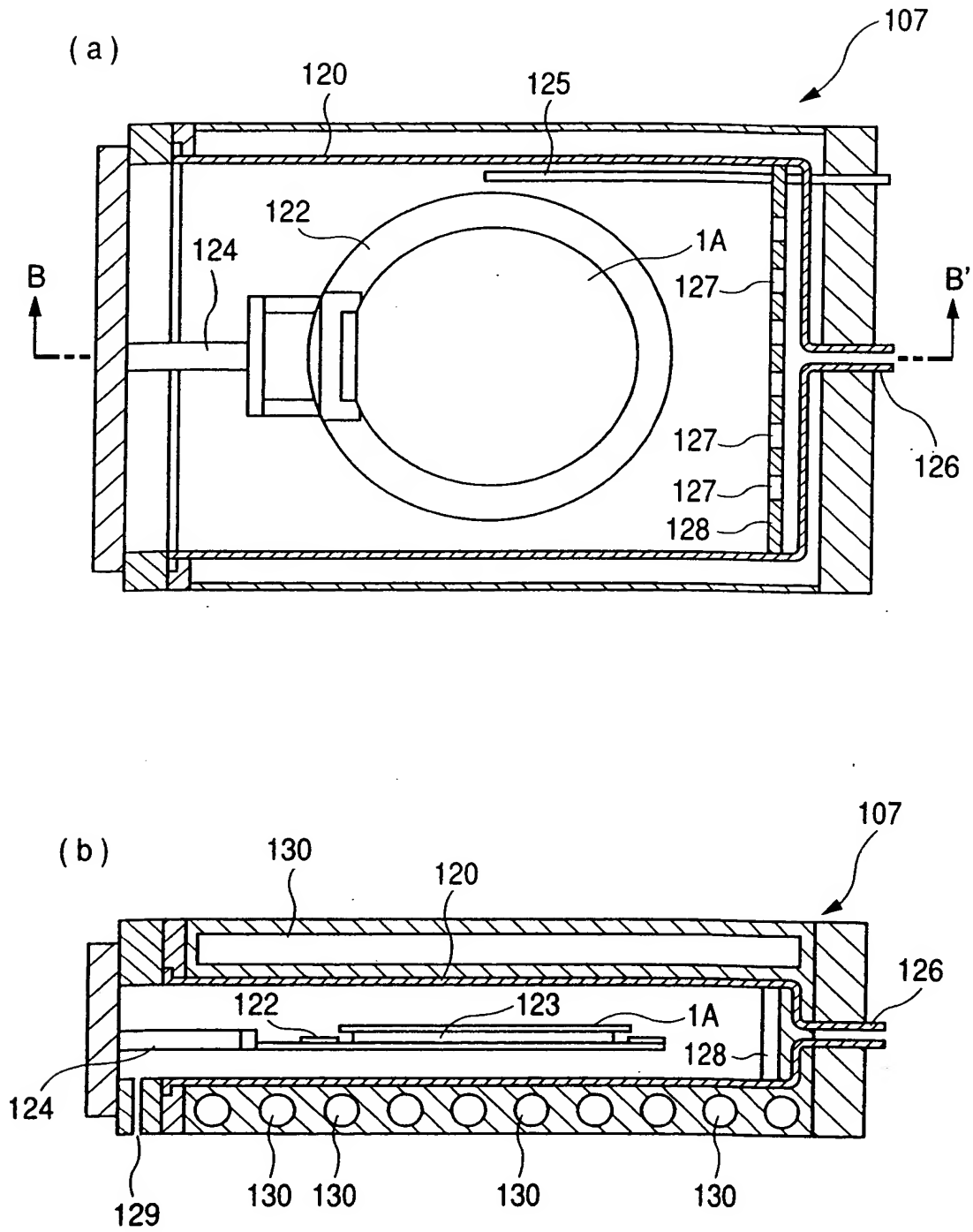
FIG. 12

FIG. 13

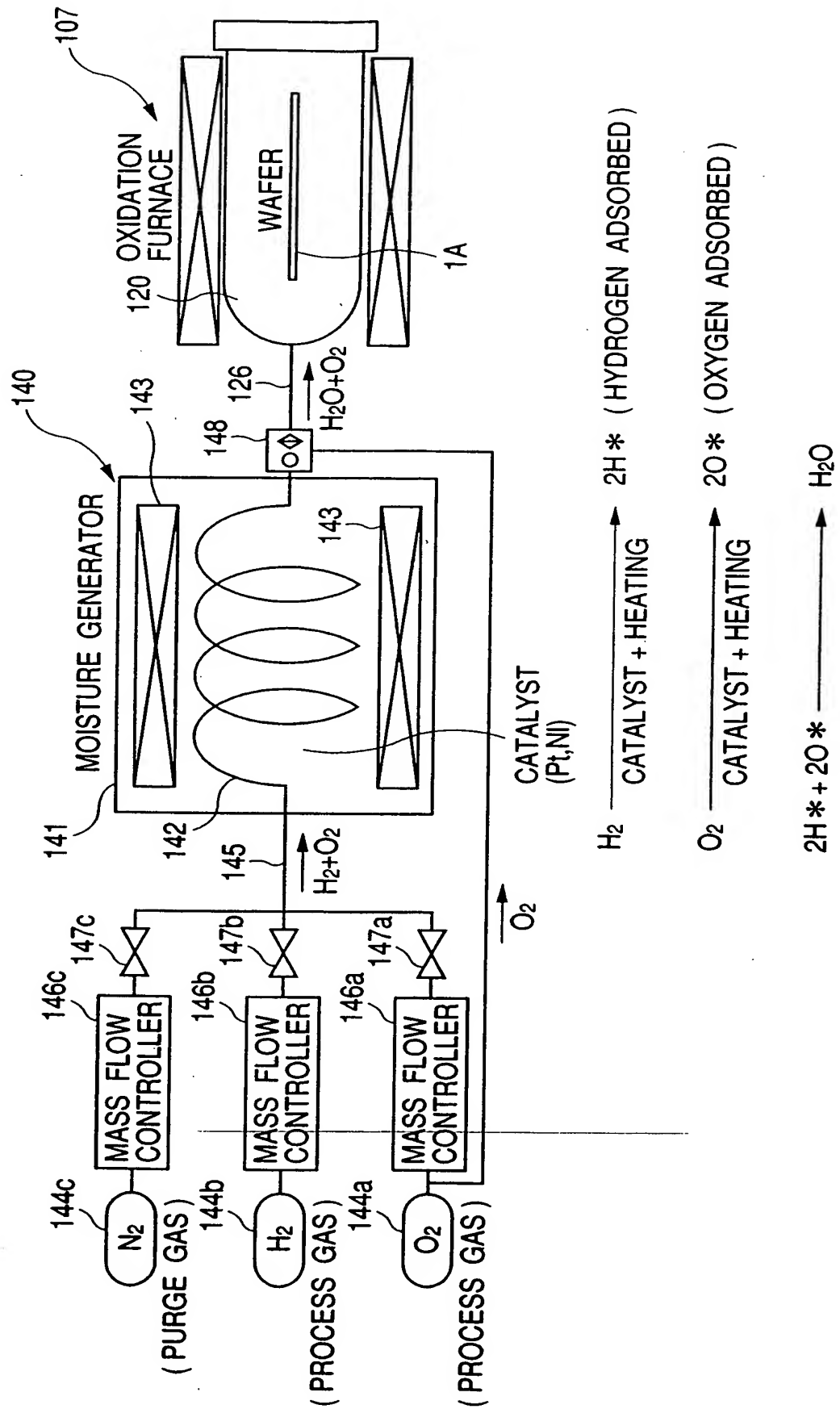


FIG. 14

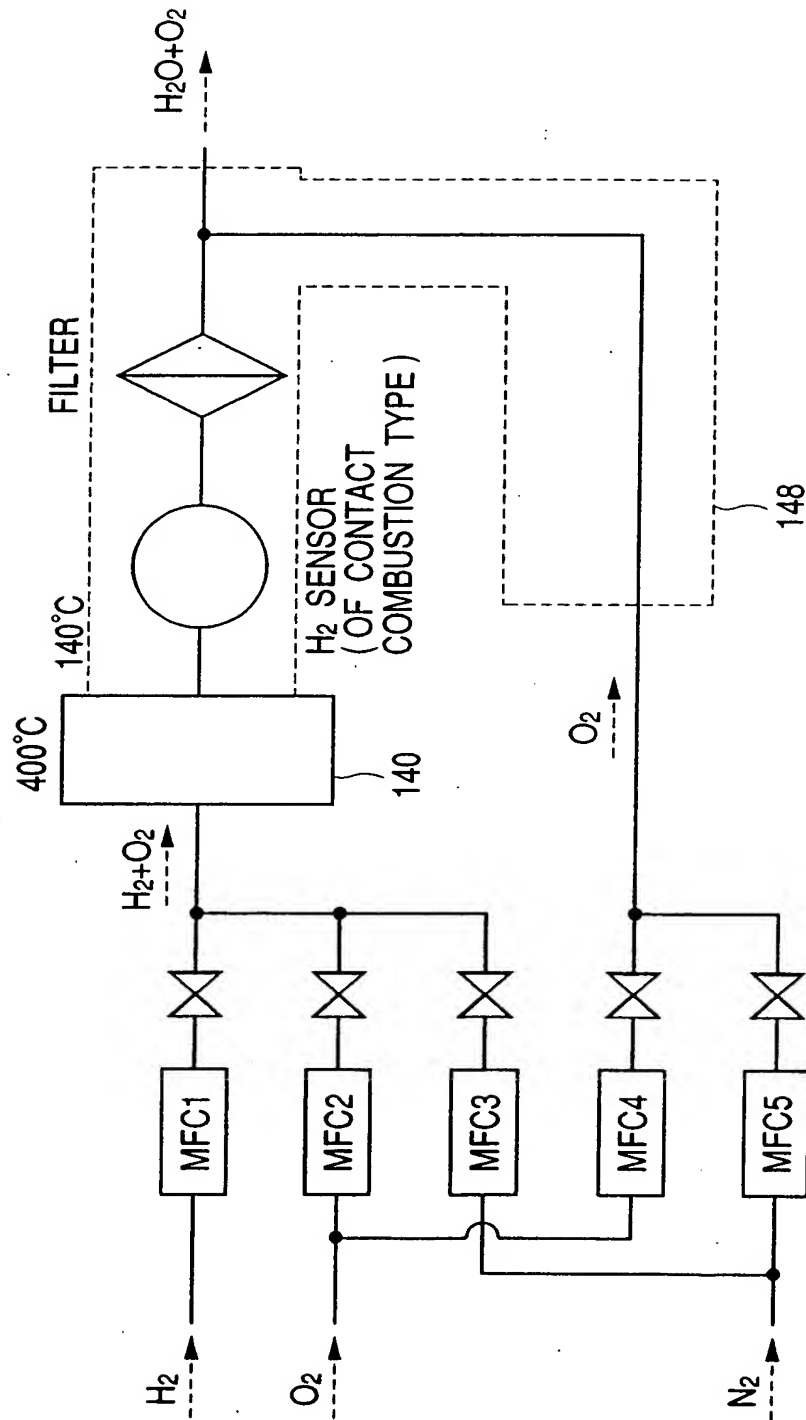


FIG. 15

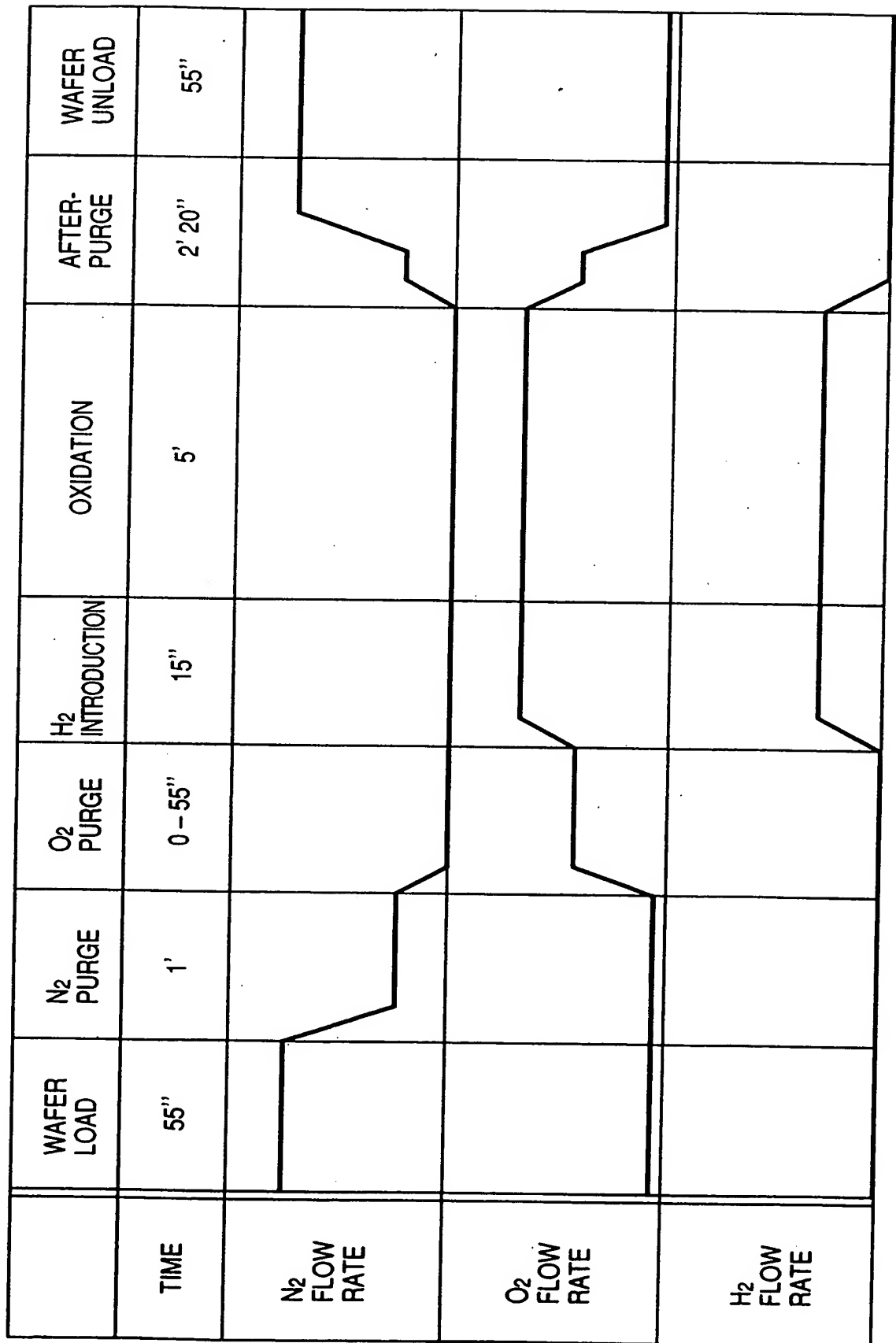


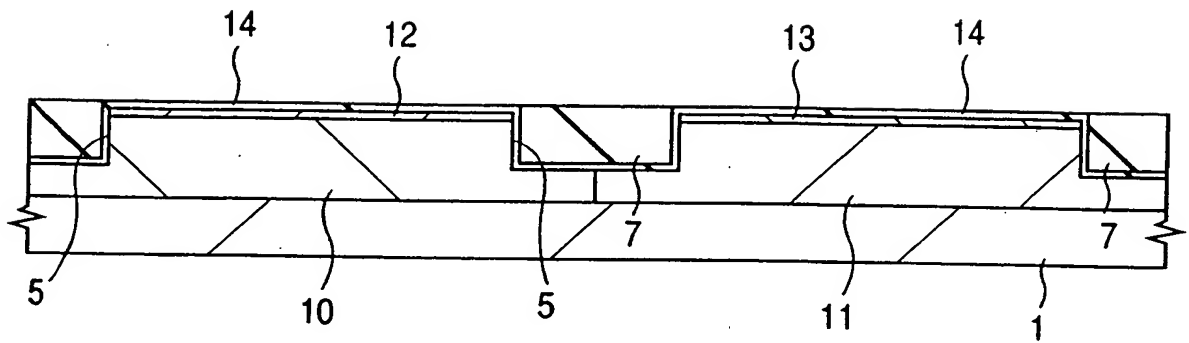
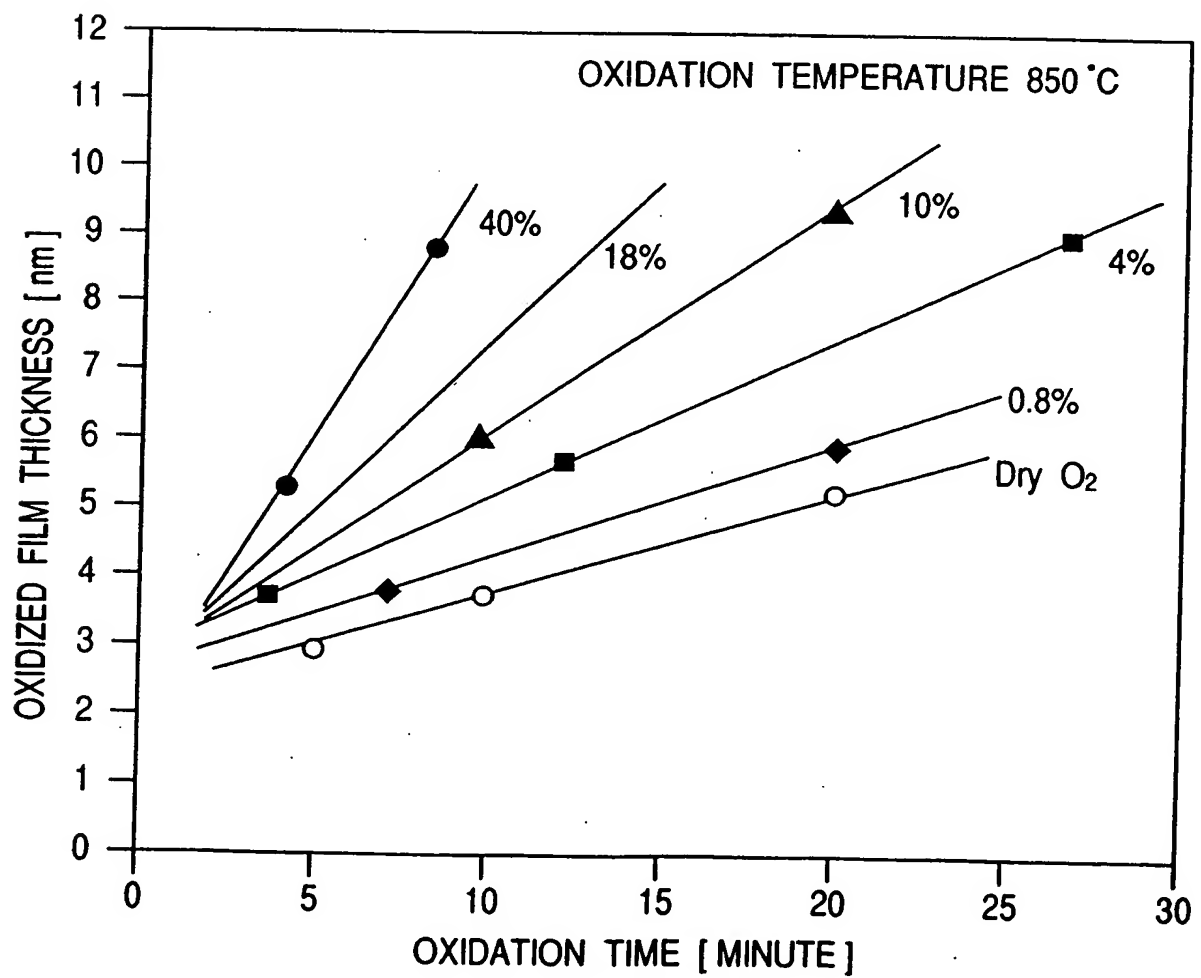
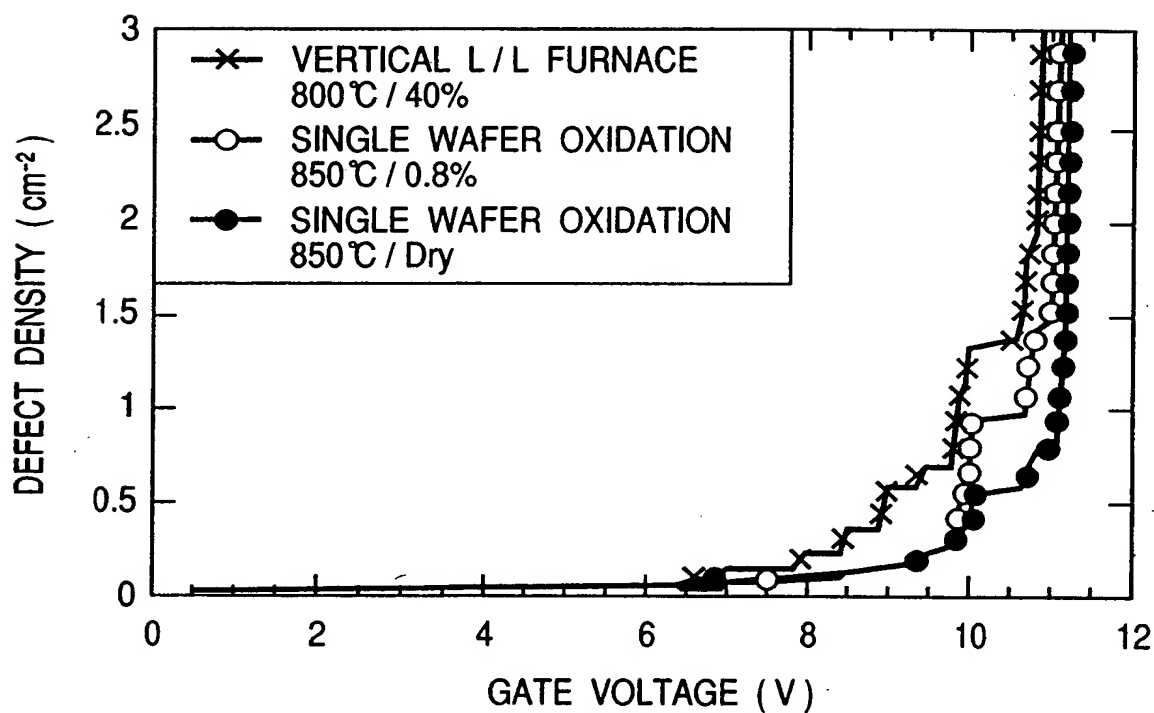
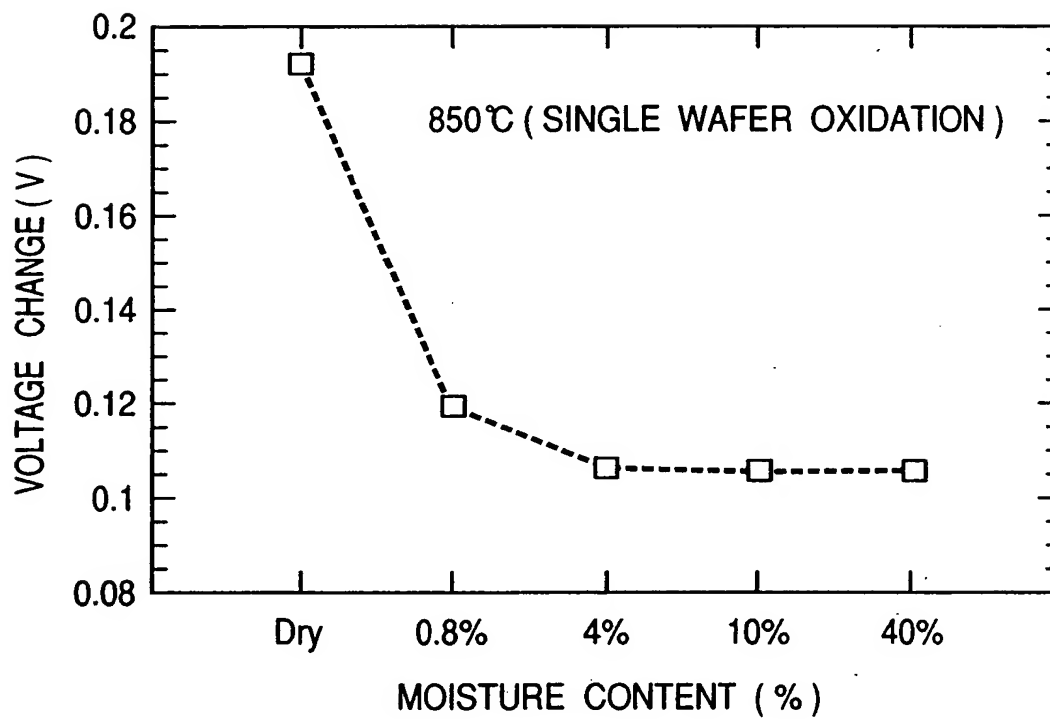
FIG. 16**FIG. 17**

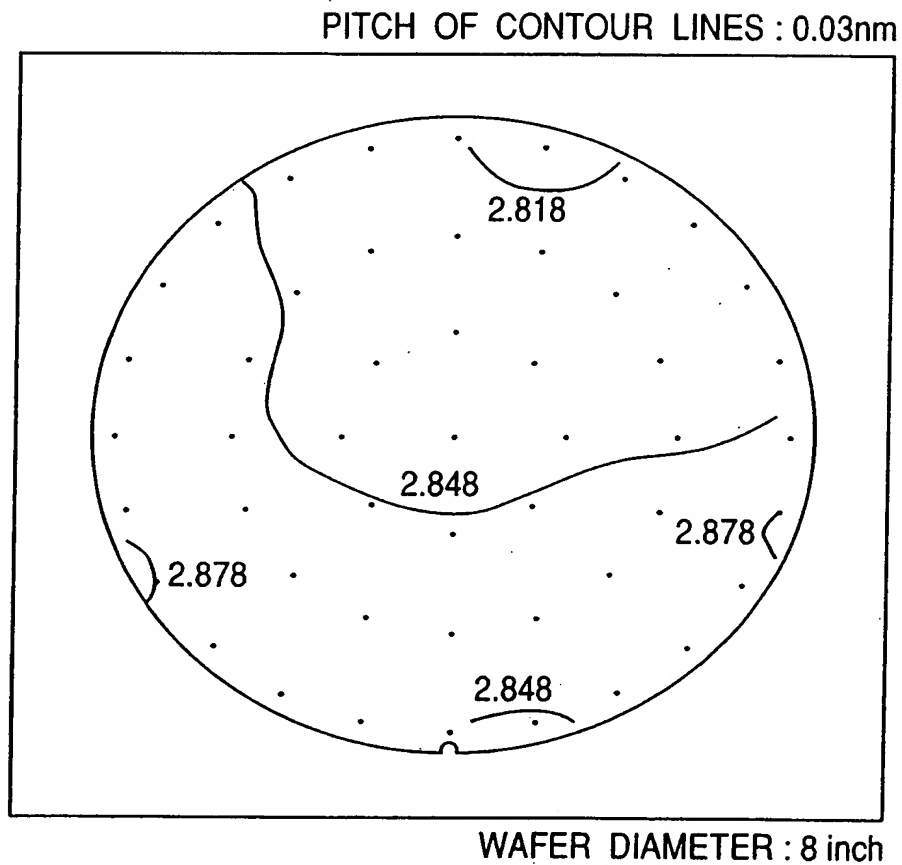
FIG. 18

INITIAL WITHSTAND VOLTAGE OF LOW MOISTURE
CONTENT OXIDE FILM
(OXIDE FILM THICKNESS = 9nm, $S = 0.19\text{cm}^2$)

FIG. 19

OXIDATION CONDITION DEPENDENCY
OF VOLTAGE CHANGE

FIG. 20



AVERAGE : 2.848 [nm]

MAX. : 2.881 [nm]

MIN. : 2.814 [nm]

MAX. - MIN. : 0.067 [nm]

± 1.18 [%]

TREATING CONDITIONS : 850°C, 2'30"

H₂ / O₂ : 0.05 / 4.9slm (MOISTURE CONTENT : 0.8%)

MEASUREMENT : AT 49 POINTS BY ELLIPSOMETER

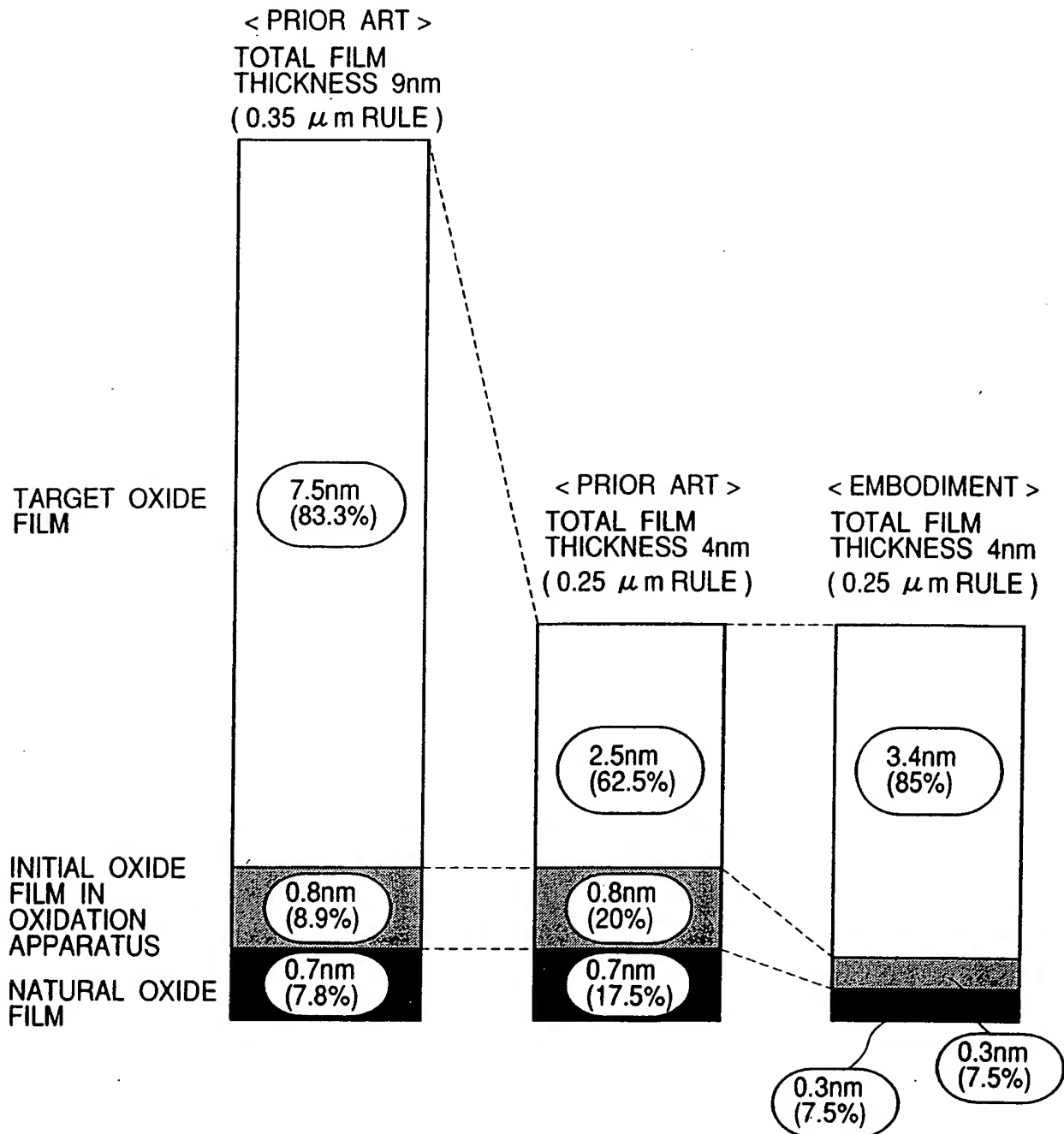
FIG. 21

FIG. 22

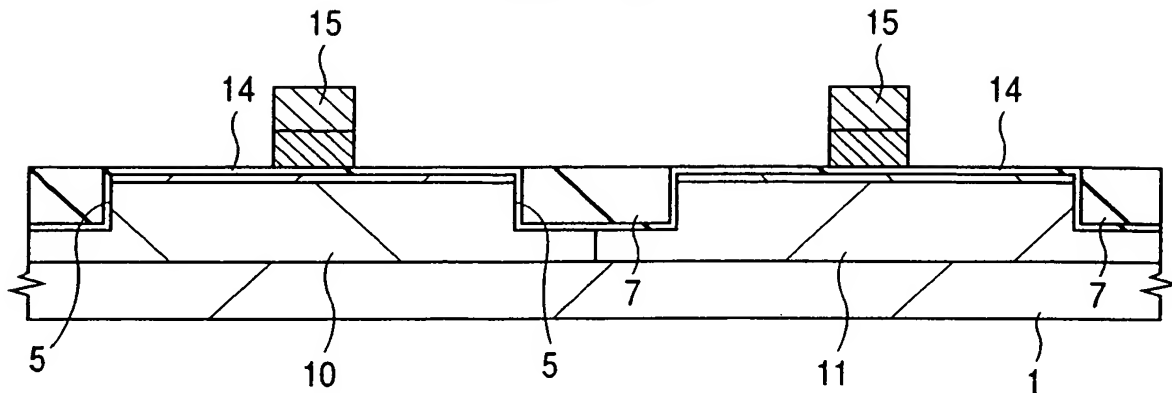


FIG. 23

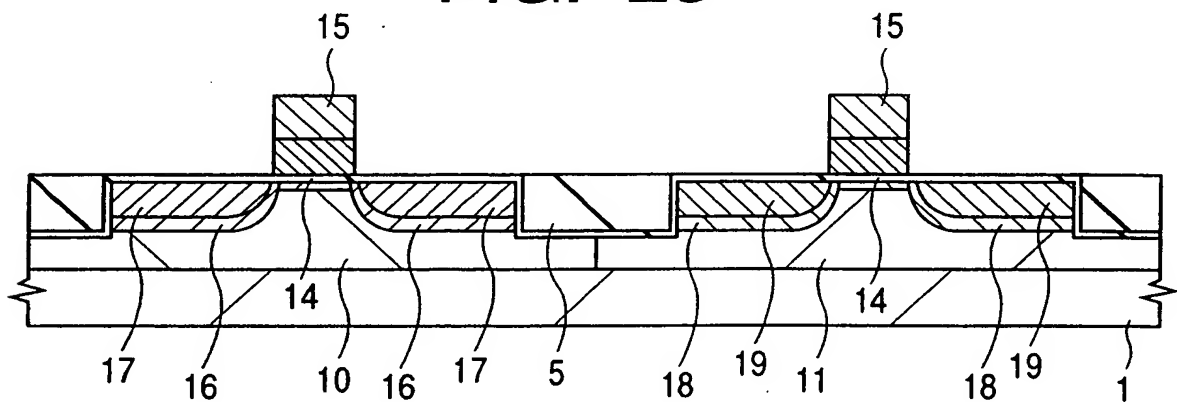


FIG. 24

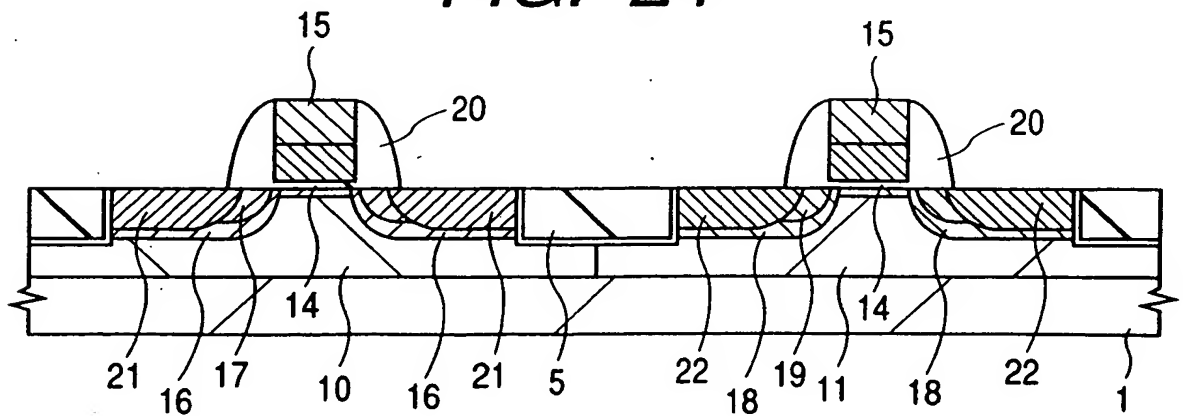


FIG. 25

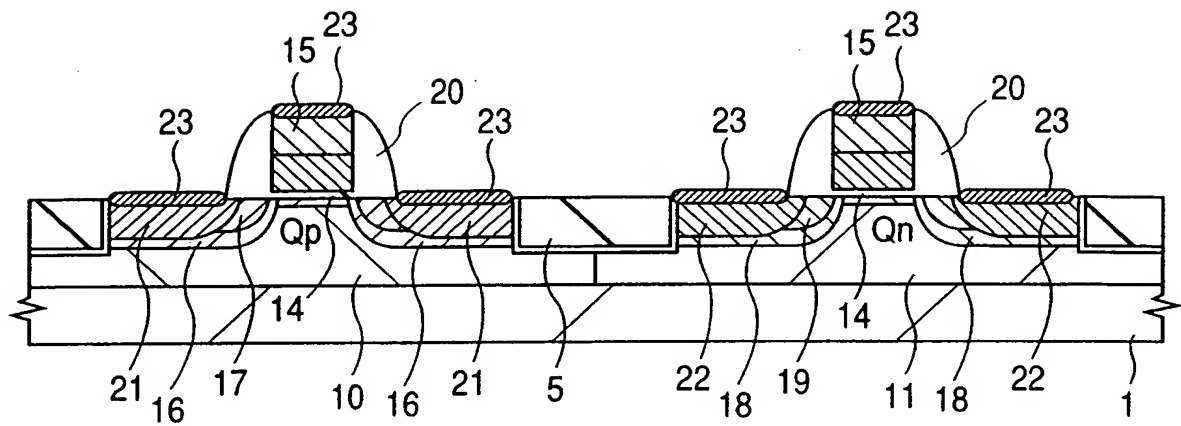


FIG. 26

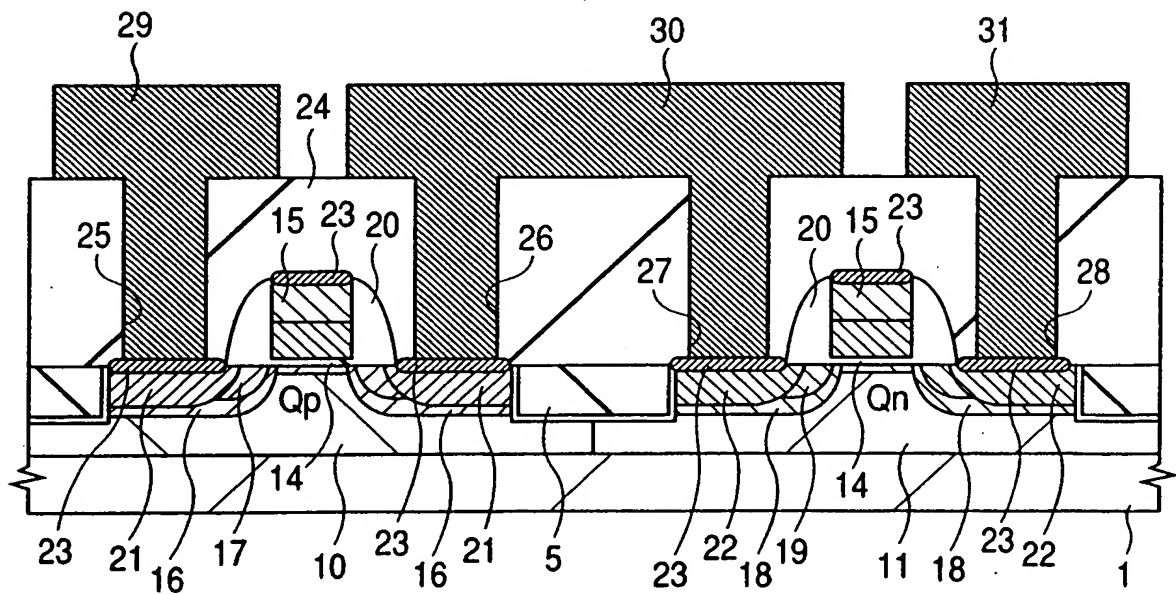


FIG. 27

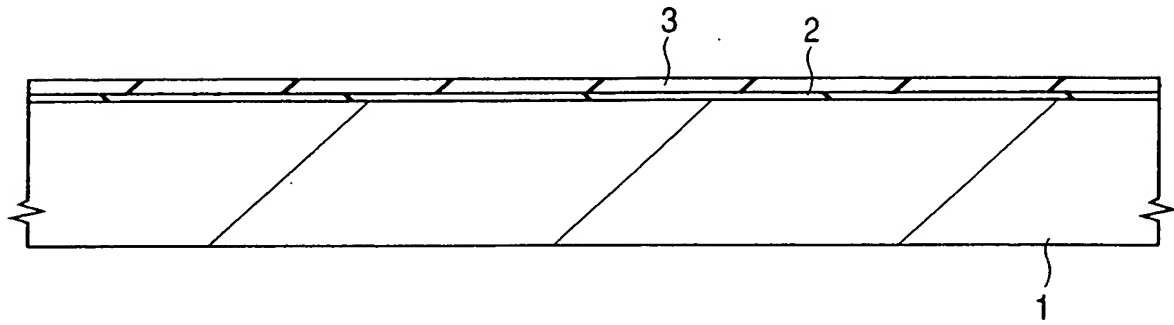


FIG. 28

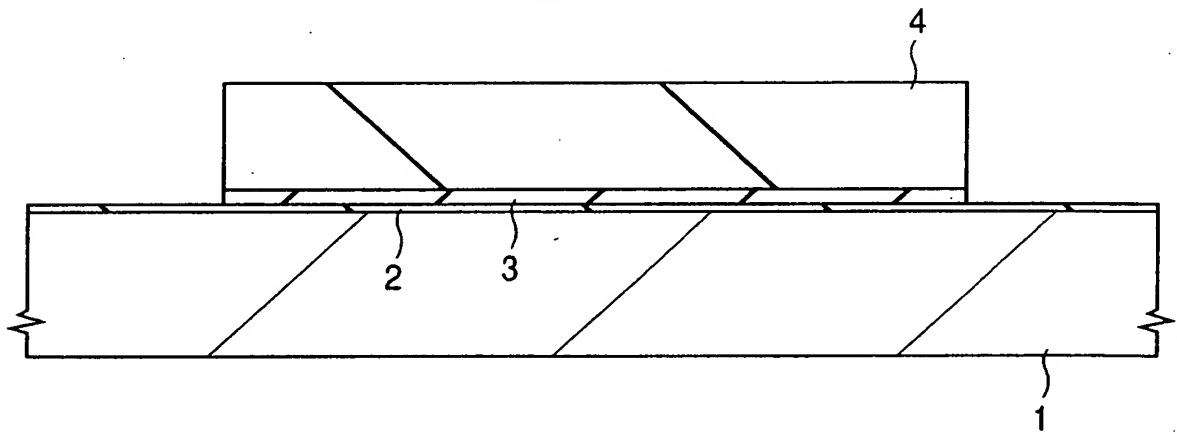


FIG. 29

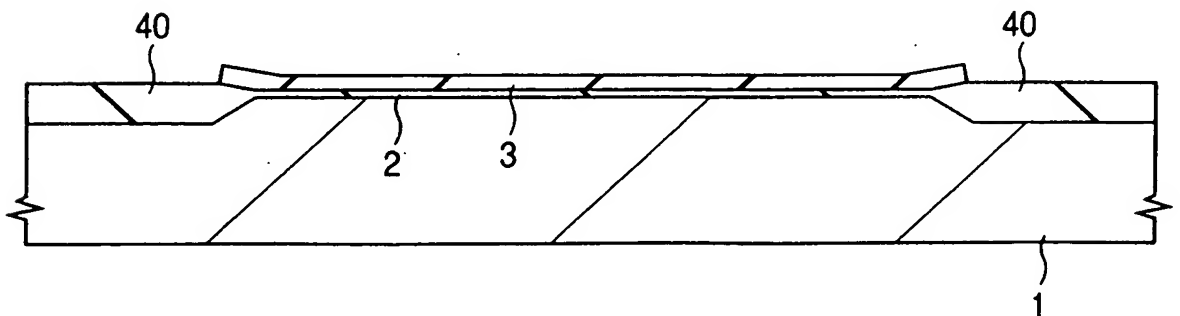


FIG. 30

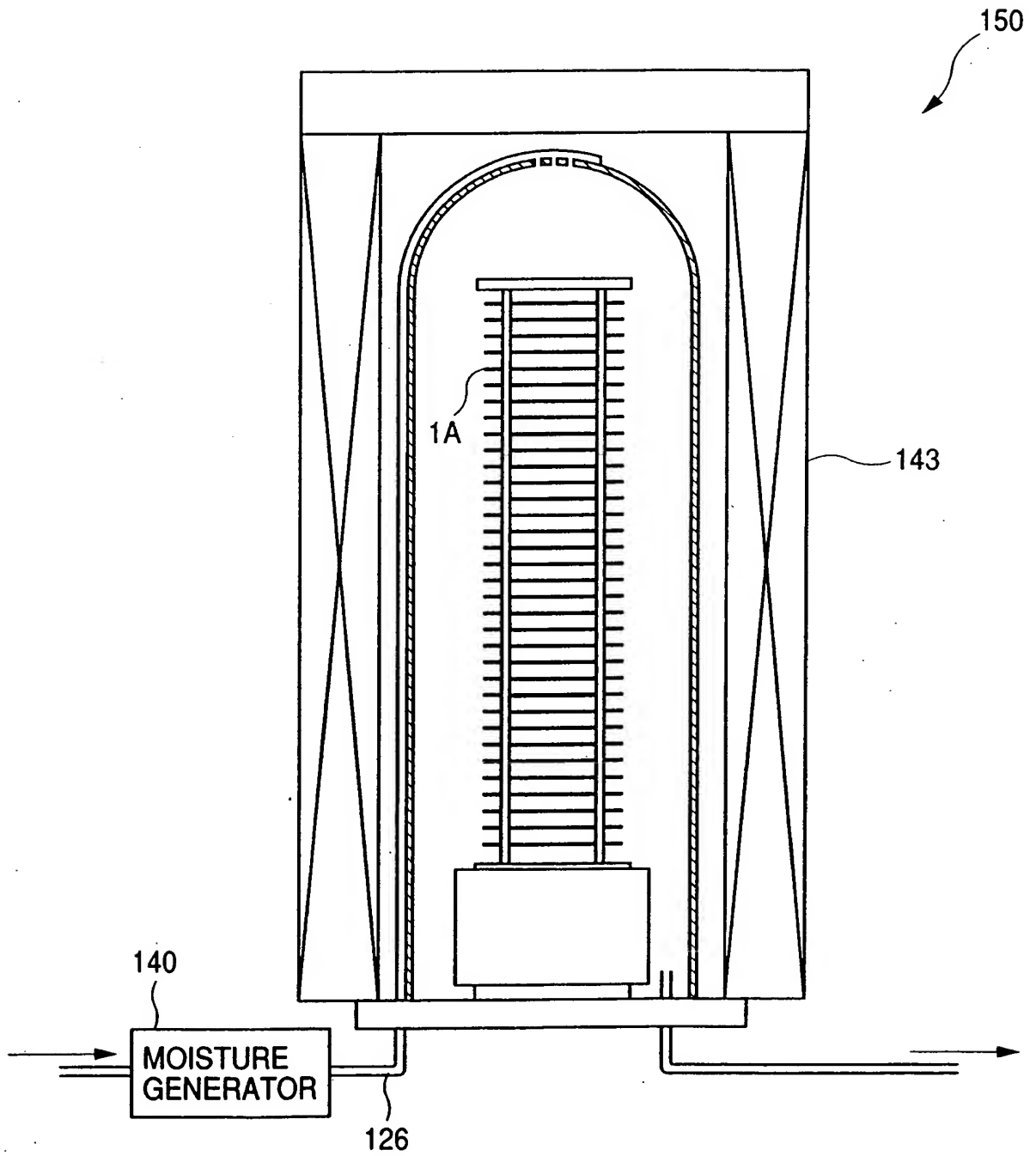


FIG. 31

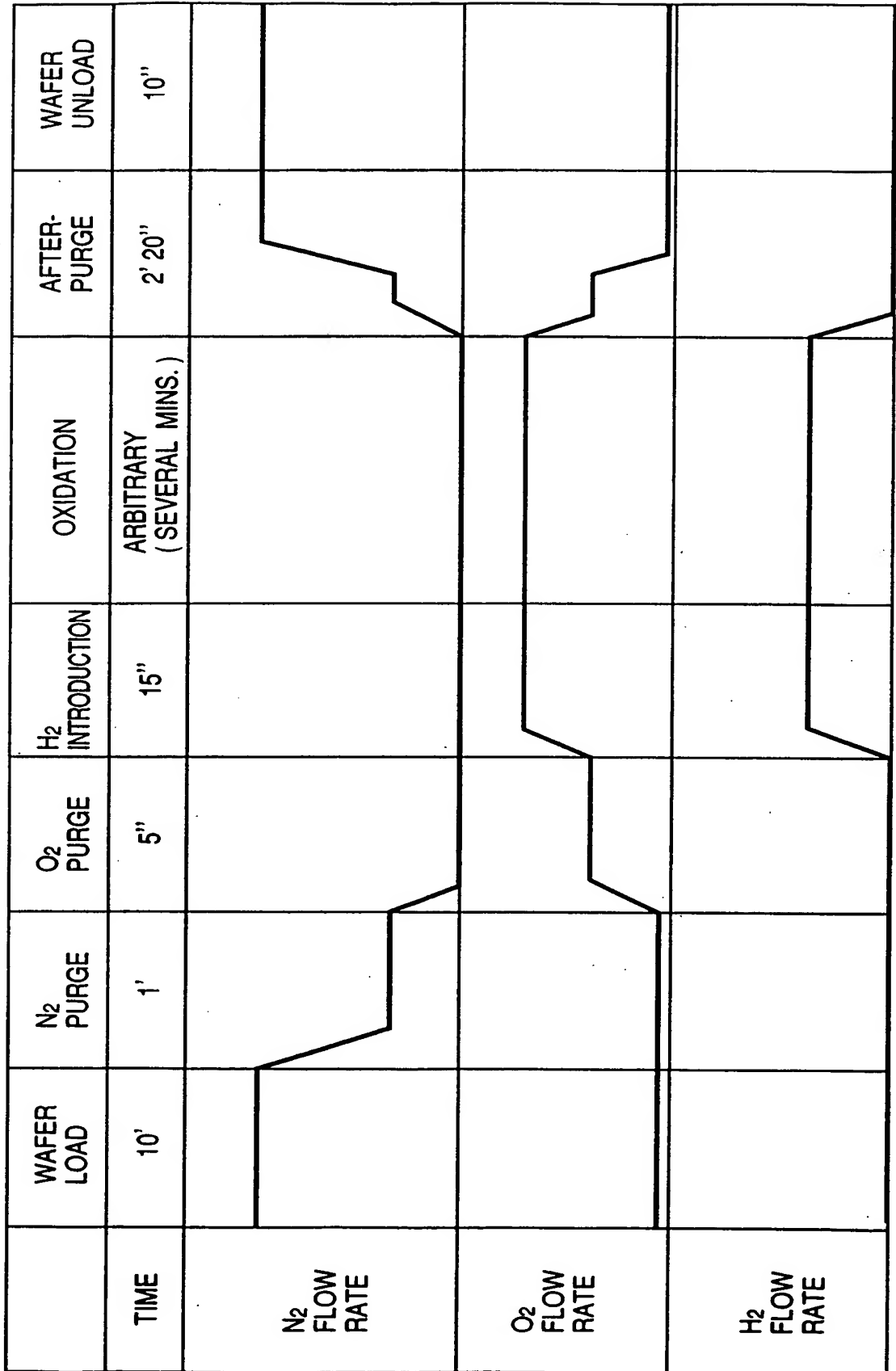


FIG. 32

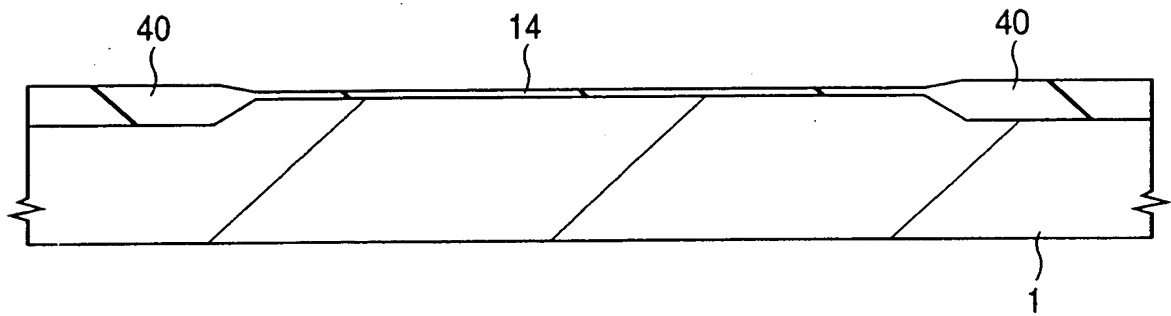


FIG. 34

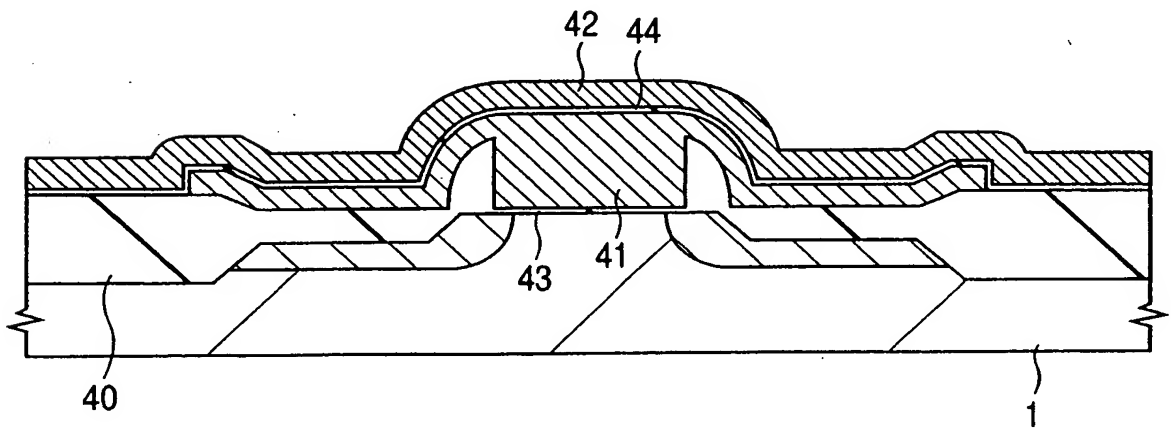


FIG. 33

